

REVISIONS													
LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED										
A	Change $t_{PLH}$ , $t_{PHL}$ , and footnotes in table I. Add figure 3. Editorial changes throughout.	1988 APR 19	<i>M. G. Lopez</i>										
<div style="border: 1px solid black; padding: 5px; width: fit-content; margin: 0 auto;">                     DEVICE 5962-86836012X IS INACTIVE FOR NEW DESIGN AS OF 17 AUG 1987. USE M38510/37501B2X.                 </div>													
REV													
SHEET													
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SHEET													
REV STATUS OF SHEETS	REV	A	A	A	A	A			A	A	A		
	SHEET	1	2	3	4	5	6	7	8	9	10		
PMIC N/A	PREPARED BY <i>Monica L. Peeling</i>		DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444										
<b>STANDARDIZED MILITARY DRAWING</b>  THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE  AMSC N/A	CHECKED BY <i>Ray Mannin</i>												
	APPROVED BY <i>[Signature]</i>												
	DRAWING APPROVAL DATE 17 AUGUST 1987		SIZE <b>A</b>	CAGE CODE <b>67268</b>	5962-86836								
	REVISION LEVEL A		SHEET 1 OF 10										

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DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.



2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections and logic diagram. The terminal connections and logic diagram shall be as specified on figure 1.

3.2.2 Truth table. The truth table shall be as specified on figure 2.

3.2.3 Switching waveforms and test circuit. The switching waveform and test circuit shall be as specified on figure 3.

3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full case operating temperature range.

3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

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TABLE I. Electrical performance characteristics. 1/ 2/

Test	Symbol	Conditions -55°C < T <sub>C</sub> < +125°C unless otherwise specified	Group A subgroups	Limits		Unit
				Min	Max	
High level output voltage	V <sub>OH</sub>	V <sub>IH</sub> = 2.0 V V <sub>CC</sub> = 4.5 V I <sub>OH</sub> = -0.4 mA	V <sub>IL</sub> = 0.8 V	1, 3	2.5	V
		3/ 4/	V <sub>IL</sub> = 0.7 V	2		
Low level output voltage	V <sub>OL</sub>	V <sub>IH</sub> = 2.0 V V <sub>CC</sub> = 4.5 V I <sub>OL</sub> = 4.0 mA	V <sub>IL</sub> = 0.8 V	1, 3	0.4	V
		4/ 5/	V <sub>IL</sub> = 0.7 V	2		
Input clamp voltage	V <sub>IC</sub>	V <sub>CC</sub> = 4.5 V I <sub>IN</sub> = -18 mA		1, 2, 3	-1.5	V
High level input current	I <sub>IH1</sub>	V <sub>CC</sub> = 5.5 V V <sub>IN</sub> = 2.7 V All other inputs = 0.0 V		1, 2, 3	20	μA
	I <sub>IH2</sub>	V <sub>CC</sub> = 5.5 V V <sub>IN</sub> = 7.0 V All other inputs = 0.0 V		1, 2, 3	100	μA
Low level input current	I <sub>IL</sub>	V <sub>CC</sub> = 5.5 V V <sub>IN</sub> = 0.4 V All other inputs = 4.5 V		1, 2, 3	-0.1	mA
Output current	I <sub>O</sub>	V <sub>CC</sub> = 5.5 V V <sub>OUT</sub> = 2.25 V 6/		1, 2, 3	-30	-112 mA
High level supply current	I <sub>CCH</sub>	V <sub>CC</sub> = 5.5 V V <sub>IN</sub> ≥ 4.5 V (All inputs)		1, 2, 3	4.0	mA
Low level supply current	I <sub>CCL</sub>	V <sub>CC</sub> = 5.5 V V <sub>IN</sub> ≤ 0.4 V (All inputs)		1, 2, 3	4.9	mA
Functional tests		See 4.3.1c 7/		7, 8		
Propagation delay time, A, B to Y	t <sub>PHL</sub>	V <sub>CC</sub> = 4.5 V to 5.5 V C <sub>L</sub> = 50 pF R <sub>L</sub> = 500Ω 8/		9, 10, 11	3	13 ns
	t <sub>PLH</sub>	See figure 3 8/		9, 10, 11	3	13.5 ns

1/ Unused inputs that do not directly control the pin under test must be ≥ 2.5 V or ≤ 0.4 V.  
 2/ Unused inputs shall not exceed 5.5 V or go less than 0.0 V. No inputs shall be floated.  
 3/ One input to gate under test must be = V<sub>IH</sub>, the other inputs shall be ≤ 0.7 V.

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- 4/ All outputs must be tested. In the case where only one input at  $V_{IL}$  maximum or  $V_{IH}$  minimum produces the proper output state, the test must be performed with each input being selected as the  $V_{IL}$  maximum or  $V_{IH}$  minimum input.
- 5/ One input to gate under test must be =  $V_{IL}$ , the other inputs shall be  $\leq 0.7$  V.
- 6/ The output conditions have been chosen to produce a current that closely approximates one-half of the true short circuit output current,  $I_{OS}$ . Not more than one output will be tested at a time and the duration of the test condition shall not exceed one second.
- 7/ Functional tests shall be conducted at input test conditions of  $0.0\text{ V} \leq V_{IL} \leq V_{OL}$  and  $V_{OH} \leq V_{IH} \leq V_{CC}$ .
- 8/ The propagation delay limits are based on single output switching. Unused inputs = 3.5 V or  $\leq 0.3$  V.

3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

4. QUALITY ASSURANCE PROVISIONS

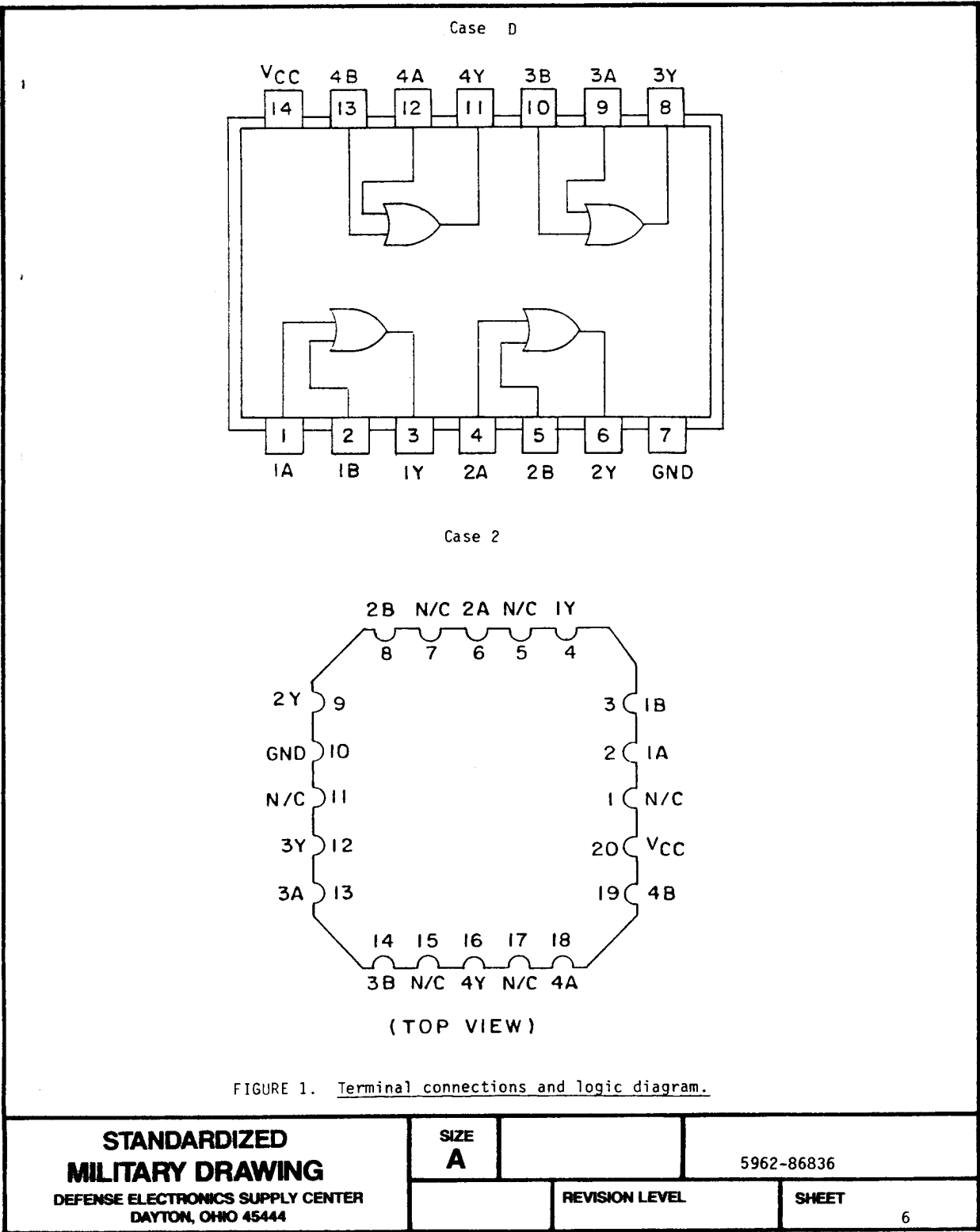
4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

- a. Burn-in test, method 1015 of MIL-STD-883.
  - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
  - (2)  $T_A = +125^\circ\text{C}$ , minimum.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

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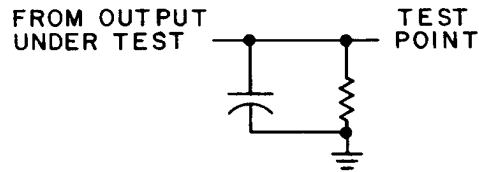


Inputs		Output
A	B	Y
H	X	H
X	H	H
L	L	L

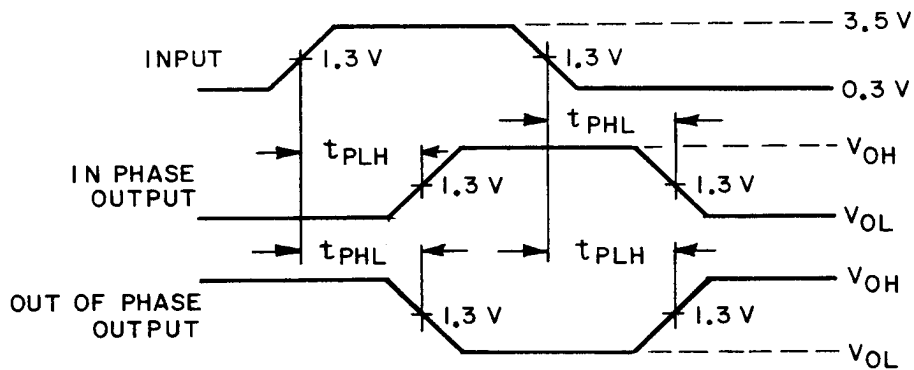
H = High voltage level  
L = Low voltage level  
X = Irrelevant

FIGURE 2. Truth table.

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LOAD CIRCUIT FOR BI-STATE TOTEM-POLE OUTPUTS



NOTES:

1.  $C_L$  includes probe and jig capacitance.
2. All input pulses have the following characteristics:  $PRR \leq 10$  MHz, duty cycle = 50%,  $t_r = t_f = 3$  ns  $\pm 1$  ns.
3. The outputs are measured one at a time with one input transition per measurement.

FIGURE 3. Switching waveform and test circuit.

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4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 4, 5, and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
- c. Subgroups 7 and 8 tests shall verify the truth table as specified on figure 2 herein.

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883:
  - (1) Test condition A, B, C or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
  - (2)  $T_A = +125^{\circ}\text{C}$ , minimum.
  - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	---
Final electrical test parameters (method 5004)	1*, 2, 3, 7, 8 9, 10, 11
Group A test requirements (method 5005)	1, 2, 3, 7, 8 9, 10, 11
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

\* PDA applies to subgroup 1.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

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6.2 Replaceability. Replaceability is determined as follows:

- a. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- b. When a QPL source is established, the part numbered device specified in this drawing will be replaced by the microcircuit identified as part number M38510/37501B--.

6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

6.4 Approved sources of supply. Approved sources of supply are listed herein. Additional sources will be added as they become available. The vendors listed herein have agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	Vendor similar part number <u>1/</u>	Replacement military specification part number
5962-8683601DX	01295 18324 27014	SNJ54ALS32W 54ALS32/BDA 54ALS32W/883	M38510/37501BDX
5962-86836012X <u>2/</u>	01295 18324 27014	SNJ54ALS32FK 54ALS32/B2A 54ALS32E/883	M38510/37501B2X

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

2/ This device is inactive for new design. Use QPL device.

<u>Vendor CAGE number</u>	<u>Vendor name and address</u>
01295	Texas Instruments, Incorporated P.O. Box 6448 Midland, TX 79701
18324	Signetics Corporation 4130 South Market Court Sacramento, CA 95834
27014	National Semiconductor Corporation 2900 Semiconductor Drive Santa Clara, CA 95051

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